



S O S G R O U P

JEOL JWS 7515
Scanning Electron Microscope (SEM)
SN WS179016-70
Vintage 1997

JEOL JWS 7515 SEM
Serial nr WS179016-70 12KV
Vintage 1997
located warehouse
150/200mm



SEM Field emission electron gun
Resolution: 8 nm
Magnification: 100x to 200,000x
Accelerating voltage: up to 12 kV
4-Axis goniometer stage.



JEOL JWS 7515 SEM
Serial nr WS179016-70 12KV
Vintage 1997
located warehouse
150/200mm



Solutions on Silicon BV

Your service partner for LAM Research Equipment

- **Equipment Support**
PM, CM, Trouble shooting, Upgrading, Training and Onsite Service Contracts
- **Process Support**
Process design, Improvement, Fab-to-Fab Transfer and Integration
- **Refurbishment**
From custom to complete refurbishment
- **Relocation**
Auditing, Fingerprinting, Decommissioning, Installation, Acceptance
- **Materials**
Supplier of first class second source materials

